



Test Report

No. :KA/2007/61074 Date: 2007/06/20 Page: 1 of 3

RALEC ELECTRONIC CORPORATION
NO. 1, CENTRAL 2ND STREET, NANTZE EXPORT PROCESSING ZONE,
KAOHSIUNG, TAIWAN

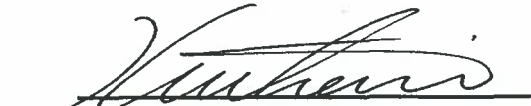


The following sample(s) was/were submitted and identified by/on behalf of the client as :

Sample Description	: LEAD FREE CHIP RESISTOR PRODUCT
Style/Item No.	: RTT06(1206T)RTT06J101
Sample Receiving Date	: 2007/06/11
Testing Period	: 2007/06/11 TO 2007/6/20

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Test Requested	: In accordance with the RoHS Directive 2002/95/EC, and its amendment directives.
Test Method	: (1) With reference to US EPA Method 3050B for Lead Content. Analysis was performed by ICP-AES.
Test Result(s)	: Please refer to next page(s).


Katherine Ho / Supervisor
Signed for and on behalf of
SGS Taiwan Limited

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